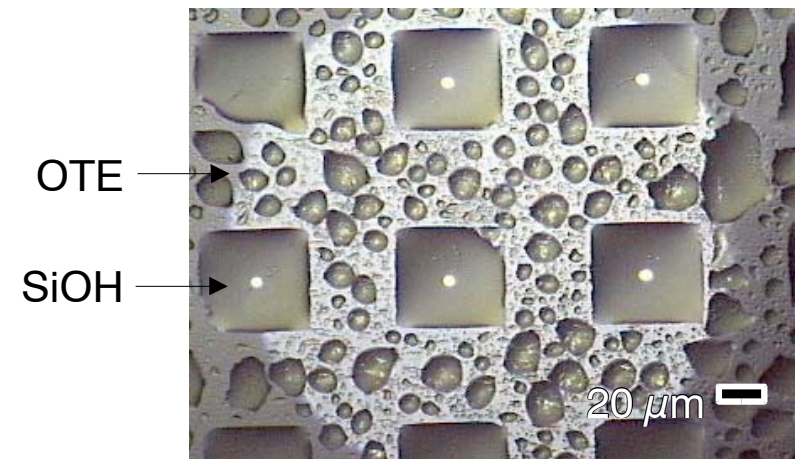
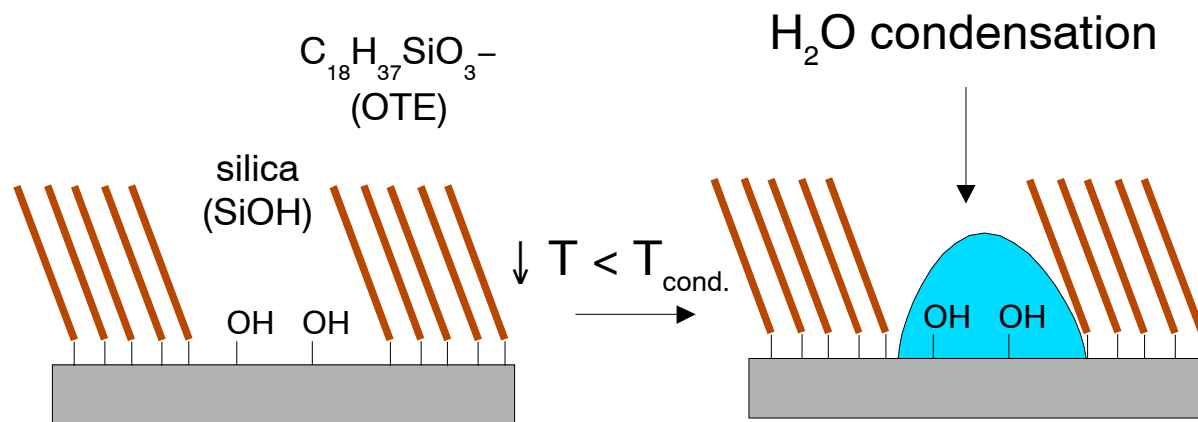


Imaging Methods: Breath Patterns

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Macromolecular Chemistry
Department Chemistry - Biology
University of Siegen

Breath / condensation pattern: By cooling a substrate below the condensation temperature H_2O will condense in different rates on the substrate with the nucleation rate of condensation depending on the surface topography and chemical composition / materials properties.

The resulting condensation pattern (with lateral dimensions above the wavelength of light) allows observation of differences in chemical surface composition (often vertically in molecular dimensions) by optical microscopy or even with the unequipped eye.

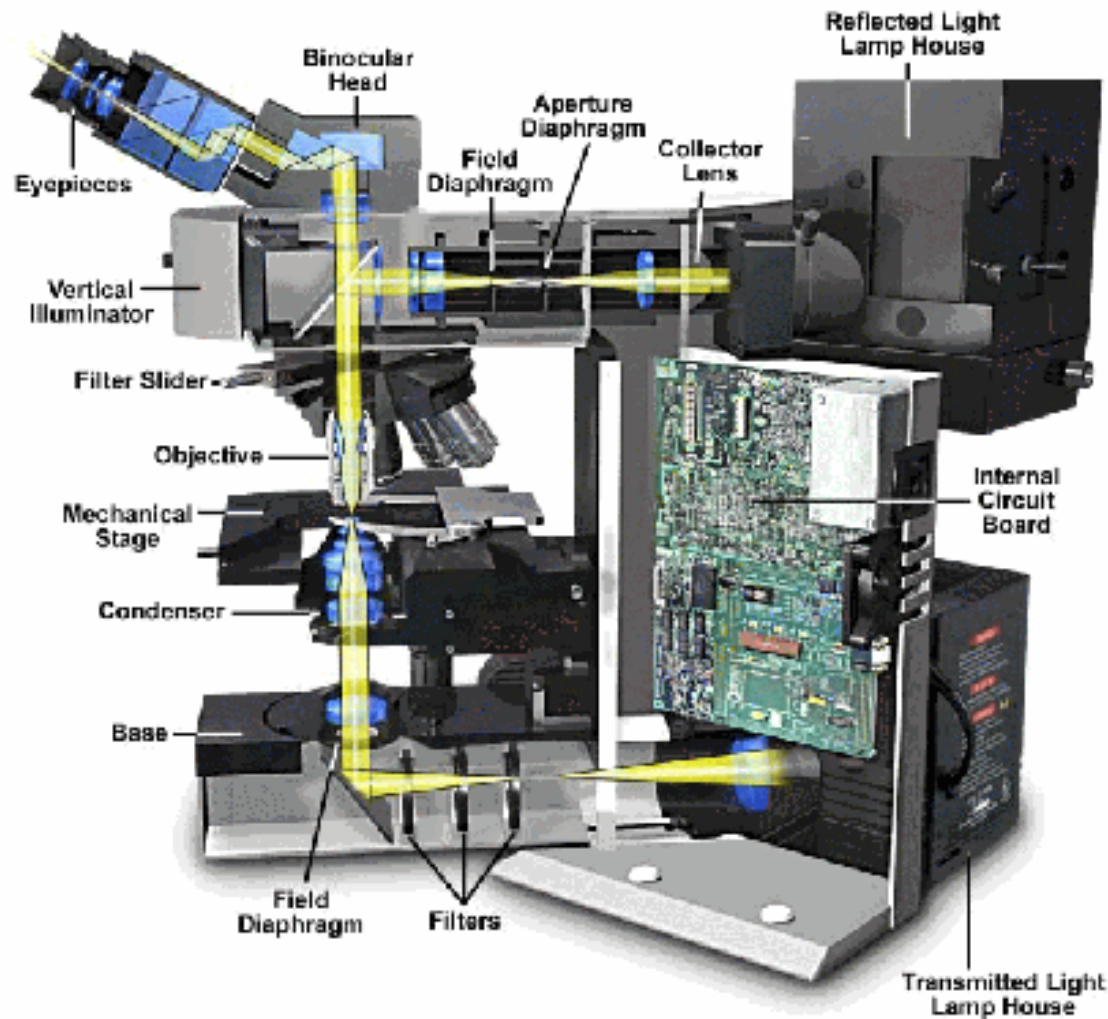


The contrast can often be increased by temperature cycling above and below the condensation temperature.

optical microscope image after H_2O condensation (octadecylsilane surface with silica squares)

Imaging Methods: Optical Microscopy

visual inspection / magnification of an object by the use of light, resolution around half the wavelength of light (practically around $0.5 \mu\text{m}$ for separated points)



two modes of illumination:

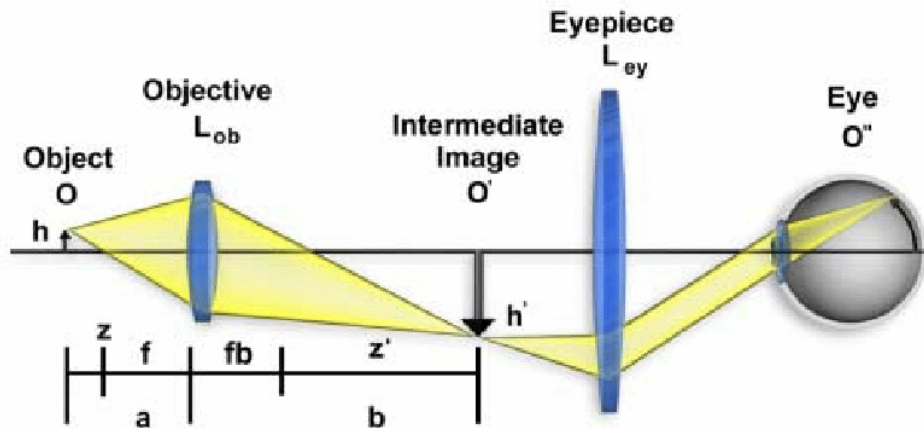
- 1) transmission: light source is on opposite side of specimen with respect to eyepieces (partially transparent samples required)
- 2) reflection: illumination from the same side as eyepieces, reflected light is observed (non-transparent samples can be investigated)

numerical aperture (NA):

$NA = r / f \rightarrow$ radius of objective r divided by the distance objective-specimen f (\sim focal distance of objective)

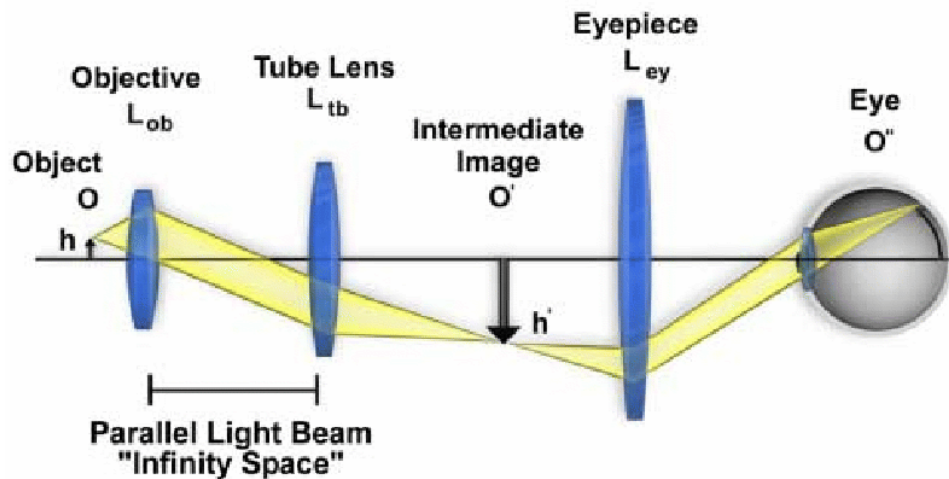
Light Paths in Optical Microscopy

Finite-Tube Length Microscope Ray Paths



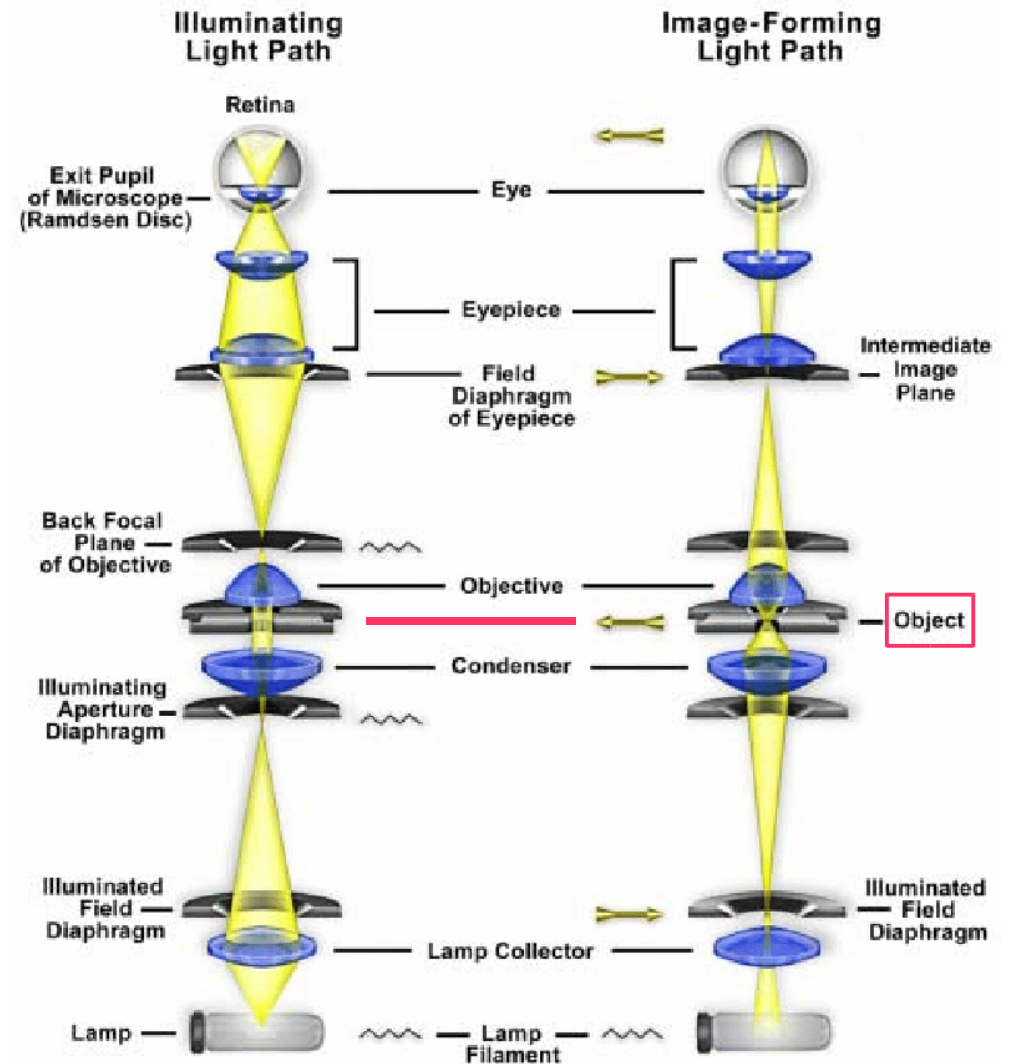
→ traditional microscopy design

Infinity-Corrected Microscope Ray Paths



→ modern design: manipulation of light in "infinite space" region, simpler, less distortion

Light Paths in Köhler Illumination



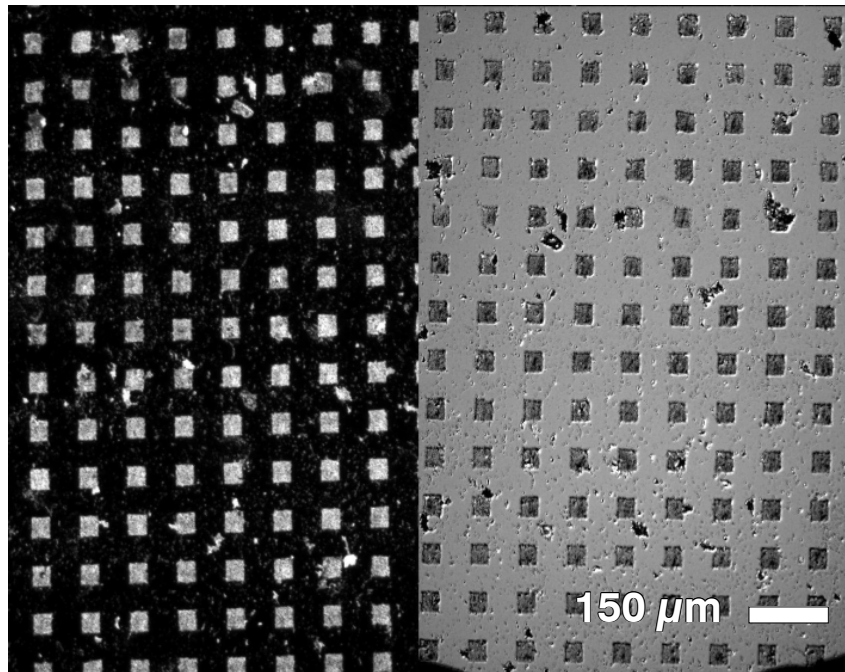
Köhler illumination provides uniform brightness over whole field of view free from glare

Optical Microscopy: Bright- and Darkfield

brightfield: conventional illumination with direct observation of light **absorption** / diffraction / reflection variations in specimen; often requires staining of sample

darkfield: striking illumination of specimen under oblique angle and observation of diffracted / reflected / refracted (scattered) light by specimen

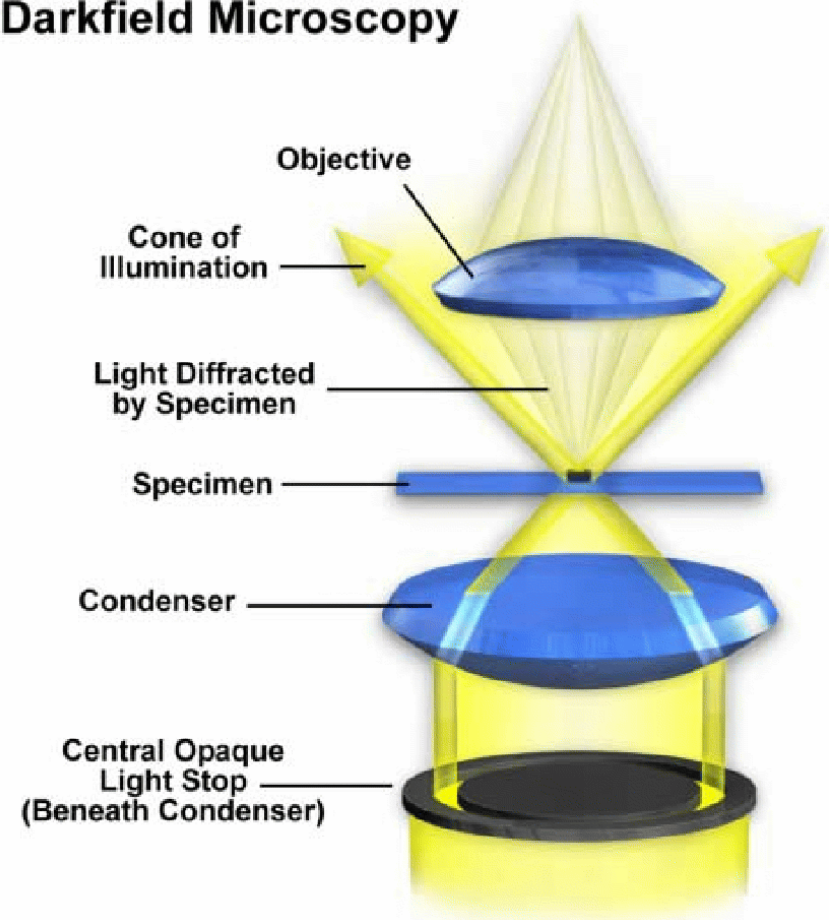
thin film of polymer colloid particles (in squares) on OTE / SiOH (squares) pattern



darkfield

brightfield (DIC)

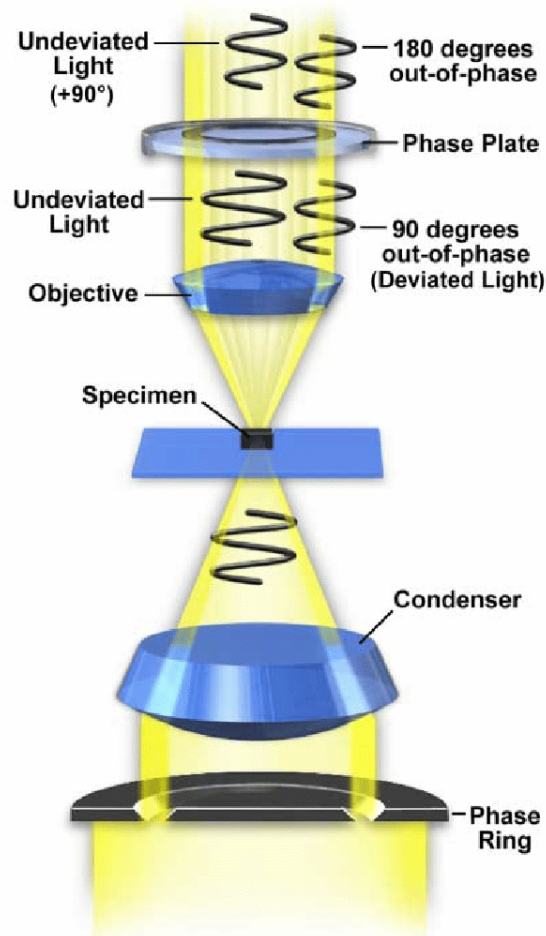
Darkfield Microscopy



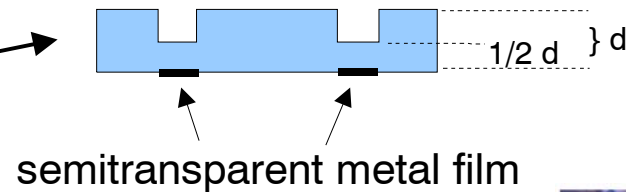
Optical Microscopy: Phase Contrast

Variations of refractive index (or thickness) in the specimen cause different light velocities and phase differences compared to undeviated (zeroth order) light around the sample. Image contrast is obtained by interference of deviated and zeroth order light (phase lag $1/2 \lambda$) at the eyepiece.

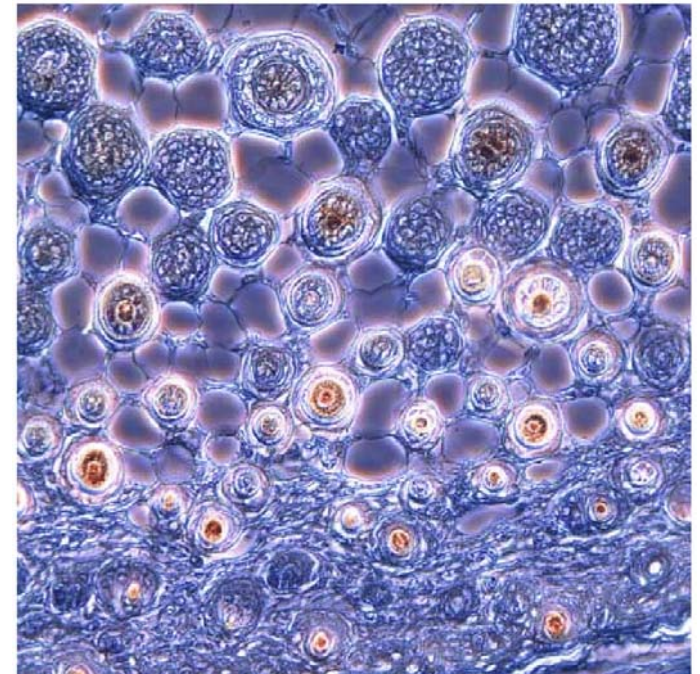
Phase Contrast Microscopy



cross section through
phase plate (transparent !)



photomicrograph of hair
cross section from a fetal
mouse taken using phase
contrast optics and a 20x
objective

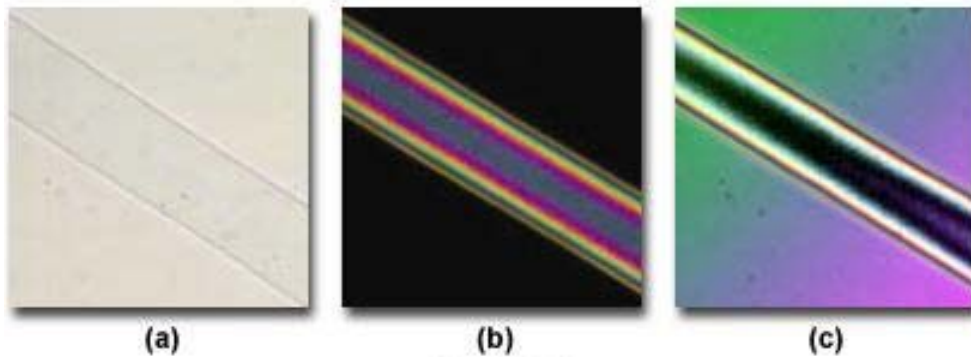


Optical Microscopy: Polarized Light

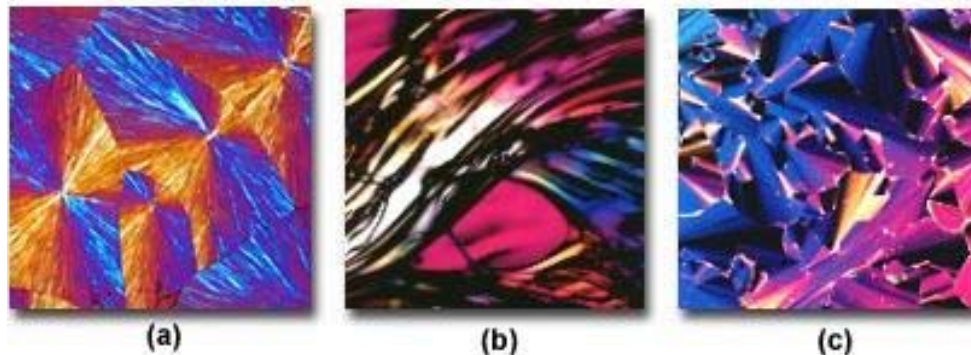
Birefringent or optically anisotropic samples (e.g. minerals, liquid crystals, oriented polymers) can be observed between two crossed plane polarizers. Variation in intensity and color occur due to different light velocities for differently oriented polarization vectors in the specimen plane, leading to the rotation of the polarization axes.

(birefringence → correlates to orientation of anisotropic crystal axes)

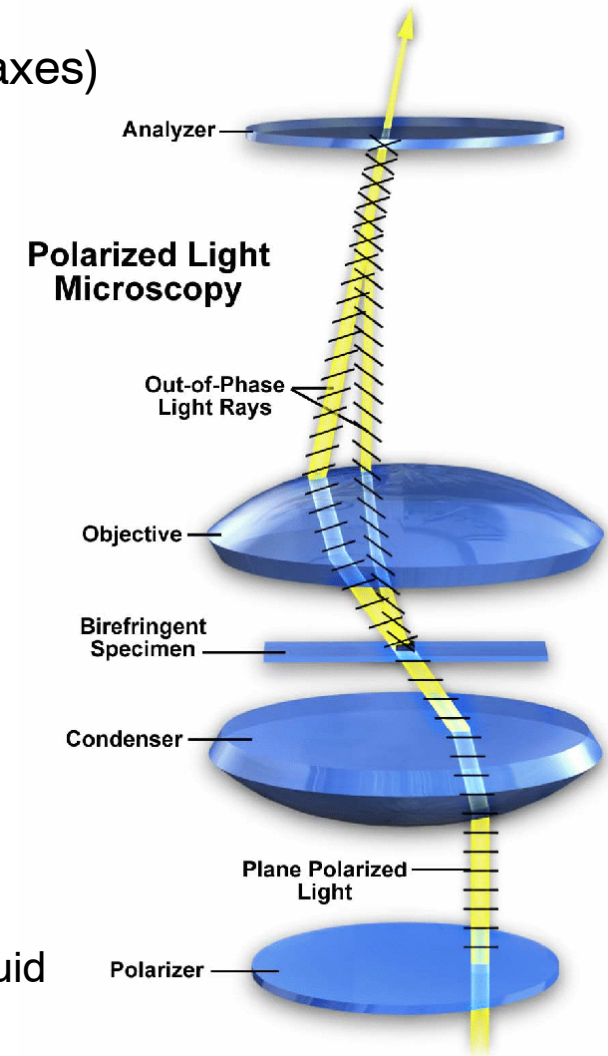
Nylon Fiber in Polarized Light



Natural and Synthetic Polymers in Polarized Light



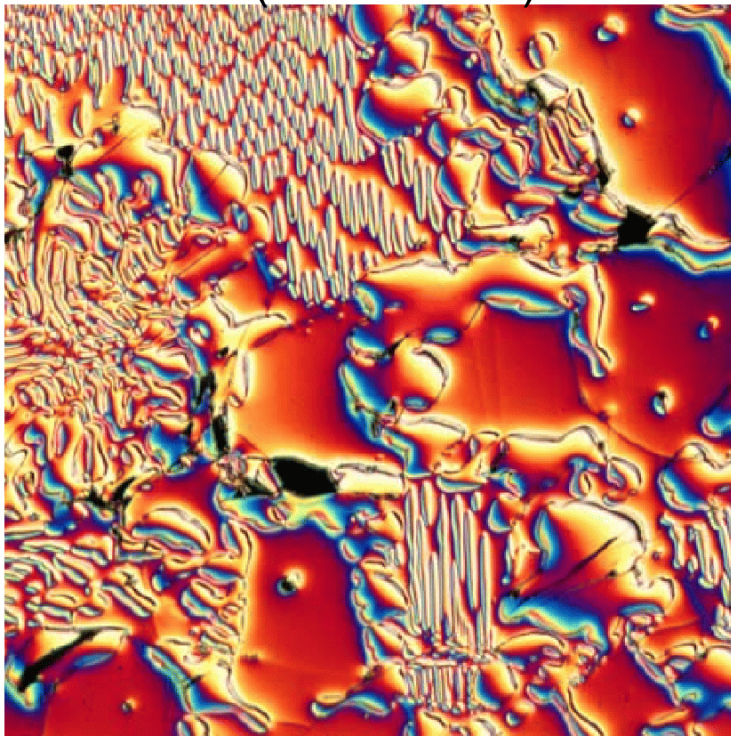
a) spherulite crystallization, b) polycarbonate without crystallization, c) liquid crystalline phase of DNA



Optical Microscopy: Differential Interference Contrast (DIC)

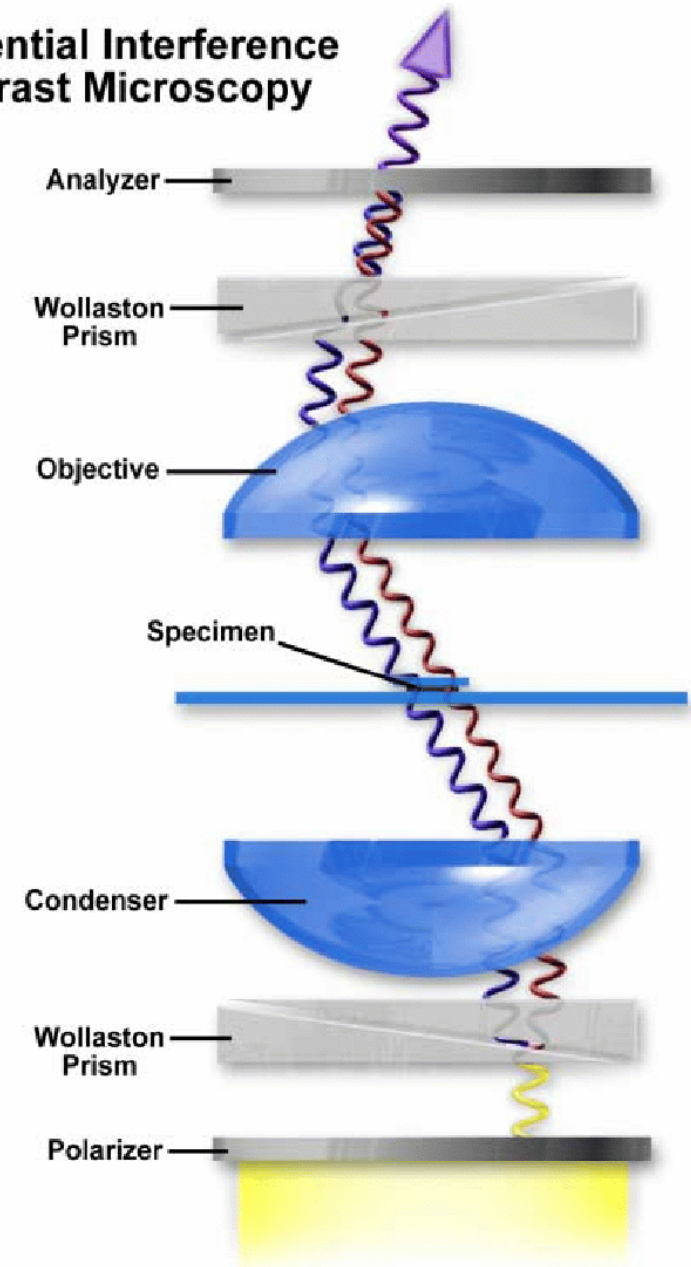
contrast enhancement of non-absorbing specimen due to variations in thickness / slope / refractive index

→ light is split into two perpendicular polarizations with minute horizontal separation (below resolution limit) and recombined (interference) after sample



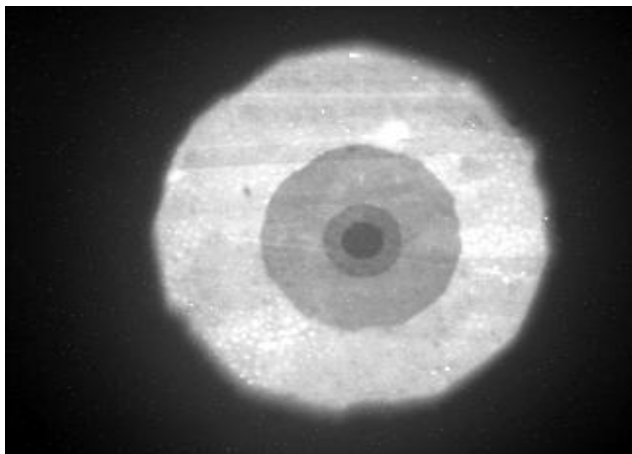
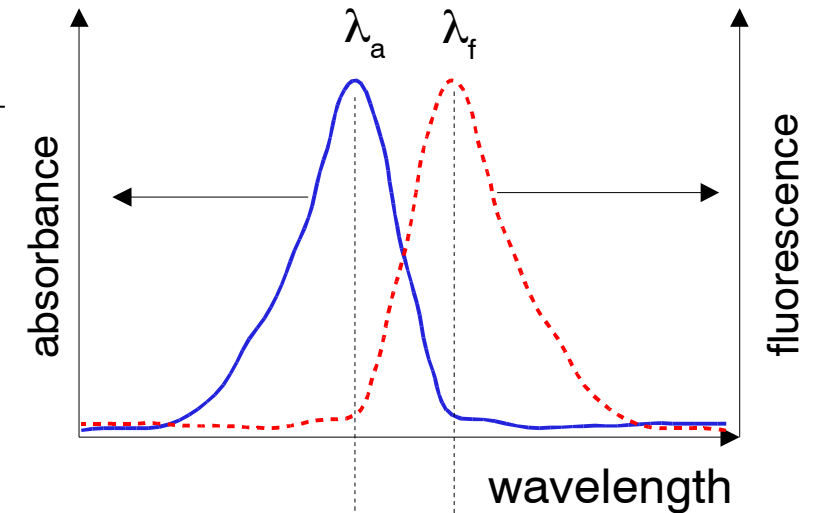
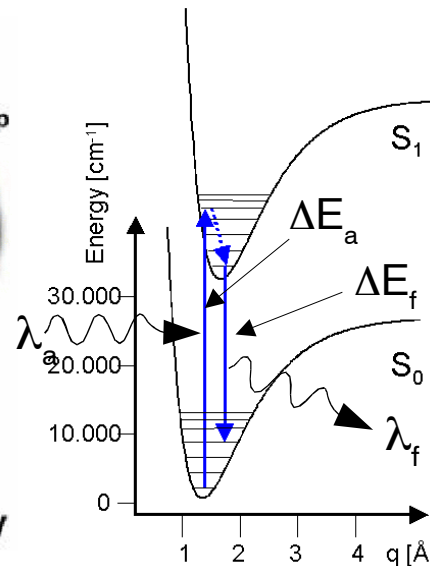
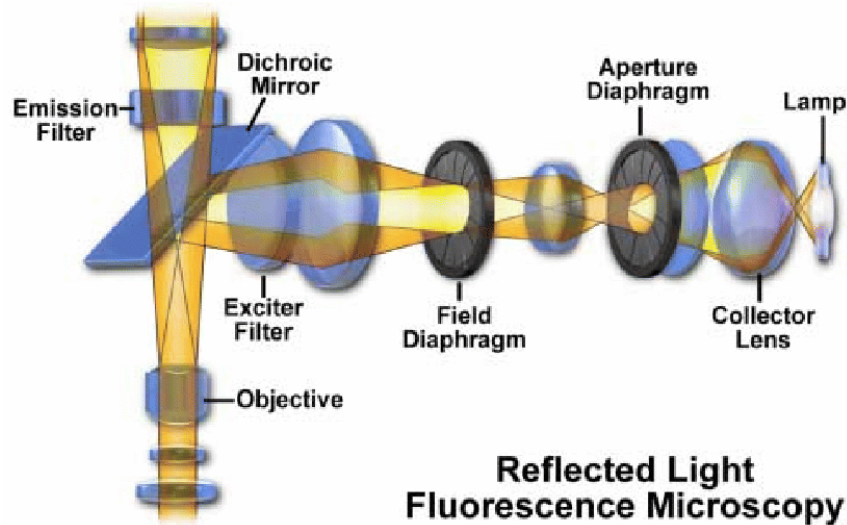
reflected light DIC of defects on the surface of a ferro-silicon alloy

Differential Interference Contrast Microscopy



Optical Microscopy: Fluorescence

chemical surface functions (like $-\text{NH}_2$) can be specifically decorated with fluorescent labels
 → bleaching with high intensity light provides contrast to unbleached regions at low fluorescence intensity



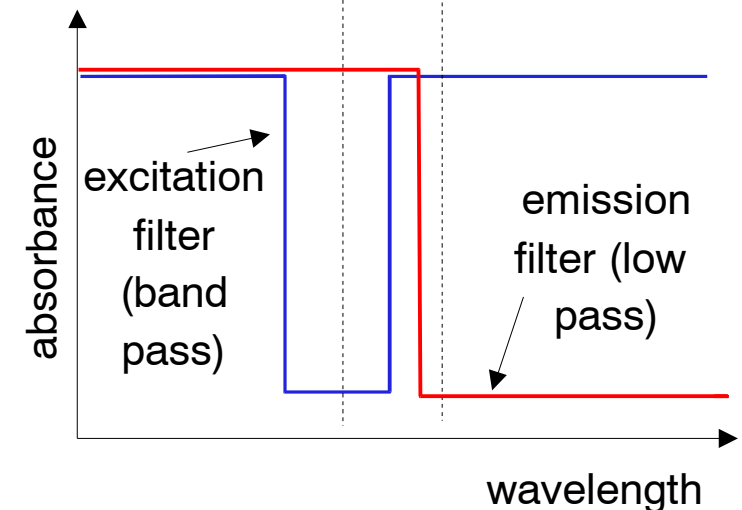
labeled and bleached amino-silane monolayer

$$\Delta E_a > \Delta E_f$$

$$h\nu_a > h\nu_f$$

$$\nu = c / \lambda$$

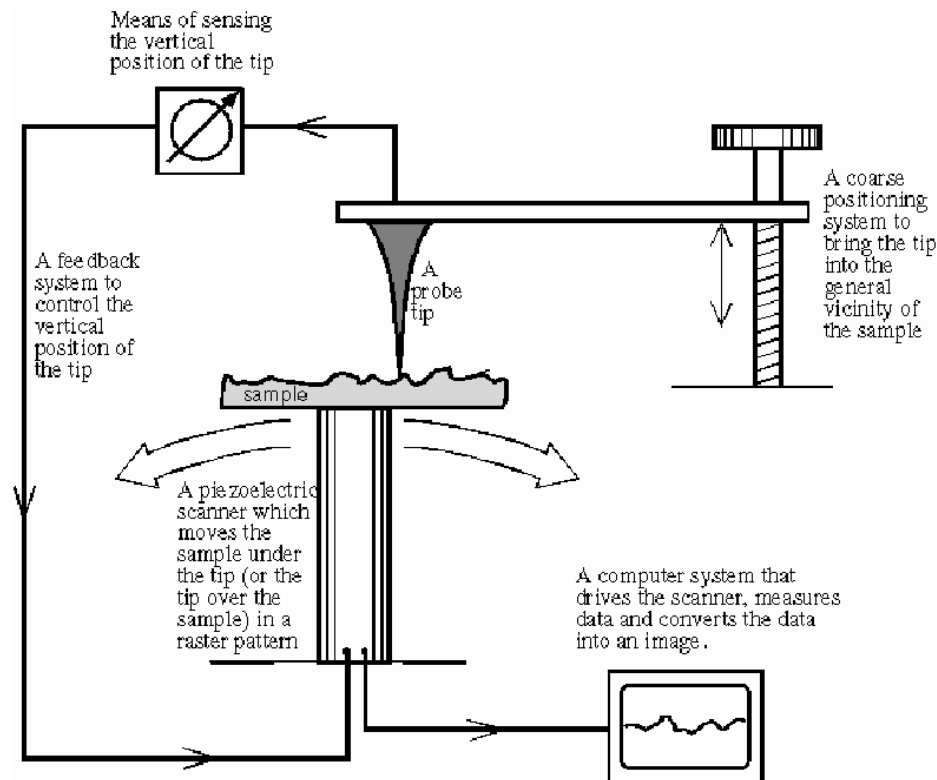
$$\rightarrow \lambda_a < \lambda_f$$



Imaging Methods: Scanning Probe Microscopy (SXM)

[...The scanning probe microscope is an imaging tool with a vast dynamic range, spanning the realms of optical and electron microscopes. It's also a profiler with unprecedented 3-D resolution. In some cases, scanning probe microscopes can measure physical properties such as surface conductivity, static charge distribution, localized friction, magnetic fields, and elastic moduli. As a result, applications of SPMs are very diverse. ...]

Rebecca Howland, Lisa Benatar, Jez Leckenby "A Practical Guide to Scanning Probe Microscopy":
<http://www.topometrix.com/spmguide/contents.htm>



fundamental principle:

A probe **tip** is brought into close **proximity** / **contact** with a **specimen** which is **scanned** in the x-y-plane. The **interaction** of the probe tip with the surface is **recorded** with respect to the **x-y-position** of the sample and converted into a **3 D map** of the measured surface property (e.g. topography, conductivity, friction, mechanical module).